

Notice of References Cited		Application/Control No. 10/817,551	Applicant(s)/Patent Under Reexamination SHIN, YONG-SHIK
		Examiner Thomas M. Redding	Art Unit 2624

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sahoo et al. Threshold Selection using a Minimal Histogram Entropy Difference, Optical Engineering 36(7) July 1997, pp 1976-1981
	V	Strang, Calculus, 1991, Wellesley-Cambridge Press, pp 130 - 133
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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